

# SGM7223 High Speed USB 2.0 (480Mbps) DPDT Analog Switch

### **GENERAL DESCRIPTION**

The SGM7223 is a high-speed, low-power double-pole/double-throw (DPDT) analog switch that operates from a single 1.8V to 4.3V power supply.

SGM7223 is designed for the switching of high-speed USB 2.0 signals in handset and consumer applications, such as cell phones, digital cameras, and notebooks with hubs or controllers with limited USB I/Os.

The SGM7223 has low bit-to-bit skew and high channel-to-channel noise isolation, and is compatible with various standards, such as high-speed USB 2.0 (480Mbps). Each switch is bidirectional and offers little or no attenuation of the high-speed signals at the outputs. Its bandwidth is wide enough to pass high-speed USB 2.0 differential signals (480Mbps) with good signal integrity.

The SGM7223 contains special circuitry on the D+/D-pins which allows the device to withstand a  $V_{BUS}$  short to D+ or D- when the USB devices are either powered off or powered on.

The SGM7223 is available in a Green TQFN-2.1×1.6-10L package. It operates over an ambient temperature range of -40°C to +85°C.

### **APPLICATIONS**

Route Signals for USB 2.0
MP3 and Other Personal Media Players
Digital Cameras and Camcorders
Portable Instrumentation
Set-Top Boxes
PDAs

### **FEATURES**

• R<sub>ON</sub> is Typically 4.5Ω at 3V

• Low Bit-to-Bit Skew: 50ps (TYP)

Voltage Operation: 1.8V to 4.3V

• Fast Switching Times:

 $t_{ON}$  = 11ns  $t_{OFF}$  = 20ns

Low Crosstalk: -33dB at 250MHz

Power-Off Protection when V<sub>+</sub> = 0V,
 D+/D- Pins can Tolerate up to 5.25V

• High Off-Isolation: -30dB at 250MHz

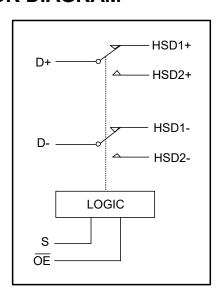
• Rail-to-Rail Input and Output Operation

Break-Before-Make Switching

• -40°C to +85°C Operating Temperature Range

• Available in a Green TQFN-2.1×1.6-10L Package

### **BLOCK DIAGRAM**



### PACKAGE/ORDERING INFORMATION

MODEL PACKAGE SPECIFIED TEMPERATURE RANGE		ORDERING NUMBER	PACKAGE MARKING	PACKING OPTION	
SGM7223	TQFN-2.1×1.6-10L	-40°C to +85°C	SGM7223YTQD10/TR	7223 XXXX	Tape and Reel, 3000

### **MARKING INFORMATION**

NOTE: XXXX = Date Code.

XXXX

Date Code - Week

Date Code - Year

Green (RoHS & HSF): SG Micro Corp defines "Green" to mean Pb-Free (RoHS compatible) and free of halogen substances. If you have additional comments or questions, please contact your SGMICRO representative directly.

### **ABSOLUTE MAXIMUM RATINGS**

V+, IN to GND	0V to 4.6V
Analog, Digital Voltage Range	0.3V to (V <sub>+</sub> ) + 0.3V
Continuous Current HSDn or Dn	±100mA
Peak Current HSDn or Dn	±150mA
Junction Temperature	+150°C
Storage Temperature Range	65°C to +150°C
Lead Temperature (Soldering, 10s)	+260°C
ESD Susceptibility	
HBM	4000V
MM	400V

### RECOMMENDED OPERATING CONDITIONS

Operating Temperature Range .....-40°C to +85°C

#### **OVERSTRESS CAUTION**

Stresses beyond those listed in Absolute Maximum Ratings may cause permanent damage to the device. Exposure to absolute maximum rating conditions for extended periods may affect reliability. Functional operation of the device at any conditions beyond those indicated in the Recommended Operating Conditions section is not implied.

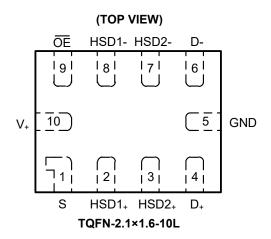
### **ESD SENSITIVITY CAUTION**

This integrated circuit can be damaged by ESD if you don't pay attention to ESD protection. SGMICRO recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage. ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

### **DISCLAIMER**

SG Micro Corp reserves the right to make any change in circuit design, or specifications without prior notice.

# **PIN CONFIGURATION**



### **PIN DESCRIPTION**

PIN	NAME	FUNCTION
1	S	Select Input.
2, 3, 8, 7, 4, 6	HSD1 <sub>+</sub> , HSD2 <sub>+</sub> , HSD1 <sub>-</sub> , HSD2 <sub>-</sub> , D <sub>+</sub> , D <sub>-</sub>	Data Ports.
5	GND	Ground.
9	ŌĒ	Output Enable.
10	V <sub>+</sub>	Power Supply.

# **FUNCTION TABLE**

ŌĒ	s	HSD1+ HSD1-	HSD2+ HSD2-
0	0	ON	OFF
0	1	OFF	ON
1	х	OFF	OFF

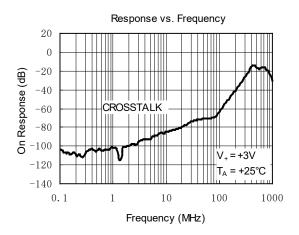
NOTE: Switches Shown For Logic "0" Input.

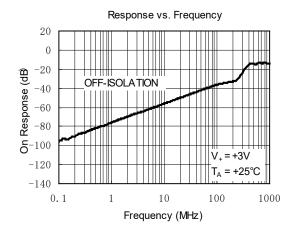
# **ELECTRICAL CHARACTERISTICS**

 $(V_{+} = 1.8V \text{ to } 4.3V, \text{ GND} = 0V, V_{IH} = 1.6V, V_{IL} = 0.5V, \text{ Full} = -40^{\circ}\text{C} \text{ to } + 85^{\circ}\text{C}.$  Typical values are at  $V_{+} = 3.3V, T_{A} = +25^{\circ}\text{C}, \text{ unless otherwise noted.})$ 

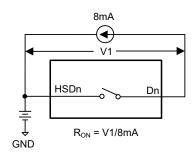
PARAMETER	SYMBOL	CONDITIONS	TEMP	MIN	TYP	MAX	UNITS
Analog Switch							
Analog I/O Voltage (HSD1 <sub>+</sub> , HSD1 <sub>-</sub> , HSD2 <sub>+</sub> , HSD2 <sub>-</sub> )	V <sub>IS</sub>		Full	0		V <sub>+</sub>	V
On-Resistance	Ron	$V_{+} = 3V$ , $V_{IS} = 0V$ to 0.4V, $I_{D} = 8mA$ ,	+25°C		4.5	8.5	Ω
OII-I (esistance	TON	Test Circuit 1	Full			9	12
On-Resistance Match between	$\Delta R_{ON}$	$V_{+} = 3V$ , $V_{IS} = 0V$ to 0.4V, $I_{D} = 8mA$ ,	+25°C		0.2	0.6	Ω
Channels	ΔI (ON	Test Circuit 1	Full			1.5	
On-Resistance Flatness	R <sub>FLAT(ON)</sub>	$V_{+} = 3V$ , $V_{IS} = 0V$ to 1.0V, $I_{D} = 8mA$ ,	+25°C		1.8	2.2	Ω
On reductino Flatinos	T TEAT (ON)	Test Circuit 1	Full			2.8	
Power Off Leakage Current (D+, D)	I <sub>OFF</sub>	$V_{+} = 0V$ , $V_{D} = 0V$ to 3.6V, $V_{S}$ , $V_{\overline{OE}} = 0V$ or 3.6V	Full			1	μΑ
Increase in I+ per Control Voltage	I <sub>CCT</sub>	$V_{+} = 3.6V$ , $V_{S}$ or $V_{\overline{OE}} = 2.6V$	Full			5	μΑ
Source Off Leakage Current	I <sub>HSD2(OFF)</sub> , I <sub>HSD1(OFF)</sub>	$V_{+} = 3.6V, V_{IS} = 3.3V/0.3V, V_{D} = 0.3V/3.3V$	Full			1	μΑ
Channel On Leakage Current	I <sub>HSD2(ON)</sub> , I <sub>HSD1(ON)</sub>	$V_{+} = 3.6V, V_{IS} = 3.3V/0.3V, V_{D} = 3.3V/0.3V \text{ or floating}$	Full			1	μA
Digital Inputs			•	•	•	•	•
Input High Voltage	V <sub>IH</sub>		Full	1.6			V
Input Low Voltage	V <sub>IL</sub>		Full			0.5	V
Input Leakage Current	I <sub>IN</sub>	$V_+ = 3V$ , $V_S$ , $V_{\overline{OE}} = 0V$ or $V_+$	Full			1	μA
Dynamic Characteristics							
Turn-On Time	t <sub>ON</sub>	$V_{IS} = 0.8V, R_L = 50\Omega, C_L = 10pF,$	+25°C		11		ns
Turn-Off Time	t <sub>OFF</sub>	Test Circuit 2	+25°C		20		ns
Break-Before-Make Time Delay	t <sub>D</sub>	$V_{IS}$ = 0.8V, $R_L$ = 50 $\Omega$ , $C_L$ = 10pF, Test Circuit 3	+25°C		5		ns
Propagation Delay	t <sub>PD</sub>	$R_L = 50\Omega$ , $C_L = 10pF$	+25°C		0.3		ns
Off Isolation	O <sub>ISO</sub>	Signal = 0dBm, $R_L$ = 50 $\Omega$ , f = 250MHz, Test Circuit 4	+25°C		-30		dB
Channel-to-Channel Crosstalk	X <sub>TALK</sub>	Signal = 0dBm, $R_L$ = 50 $\Omega$ , f = 250MHz, Test Circuit 5	+25°C		-33		dB
-3dB Bandwidth	BW	Signal = 0dBm, $R_L$ = 50 $\Omega$ , $C_L$ = 5pF Test Circuit 6	+25°C		500		MHz
Channel-to-Channel Skew	t <sub>SKEW</sub>	$R_L = 50\Omega$ , $C_L = 10pF$	+25°C		0.05		ns
Charge Injection Select Input to Common I/O	Q	$V_G = GND, C_L = 1nF, R_G = 0\Omega,$ $Q = C_L \times V_{OUT}, Test Circuit 7$	+25°C		9.8		pC
HSD <sub>+</sub> , HSD <sub>-</sub> , D <sub>+</sub> , D <sub>-</sub> On Capacitance	C <sub>ON</sub>		+25°C		6.5		pF
Power Requirements							
Power Supply Range	V <sub>+</sub>		Full	1.8		4.3	V
Power Supply Current	I <sub>+</sub>	$V_+ = 3V$ , $V_S$ , $V_{\overline{OE}} = 0V$ or $V_+$	Full			1	μA

# TYPICAL PERFORMANCE CHARACTERISTICS

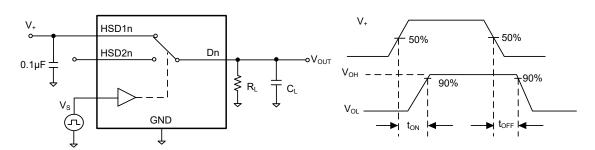




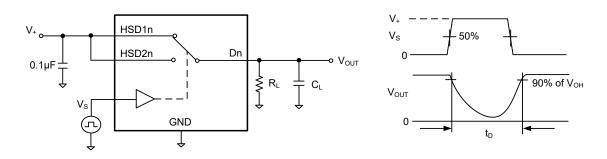
# **TEST CIRCUITS**



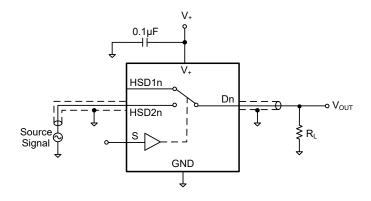
Test Circuit 1. On-Resistance



Test Circuit 2. Switching Times (ton, toff)

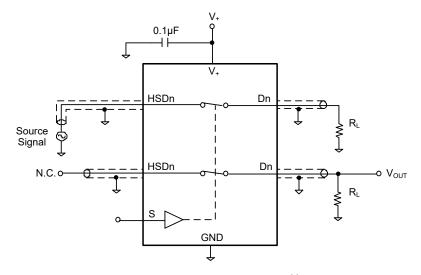


Test Circuit 3. Break-Before-Make Time (t<sub>D</sub>)



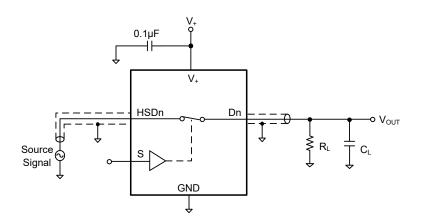
**Test Circuit 4. Off Isolation** 

# **TEST CIRCUITS (continued)**

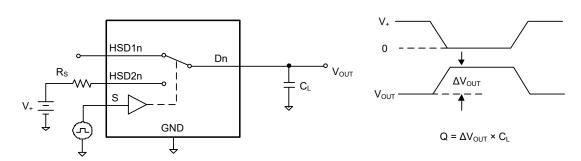


Channel-to-Channel Crosstalk = -20 × log  $\frac{V_{HSDn}}{V_{OUT}}$ 

Test Circuit 5. Channel-to-Channel Crosstalk



Test Circuit 6. -3dB Bandwidth



Test Circuit 7. Charge Injection (Q)

### **APPLICATION INFORMATION**

### Meeting USB 2.0 V<sub>BUS</sub> Short Requirements

In section 7.1.1 of the USB 2.0 specification, it notes that USB devices must be able to withstand a  $V_{\text{BUS}}$  short to D+ or D- when the USB devices is either powered off or powered on. The SGM7223 can be successfully configured to meet both these requirements.

#### **Power-Off Protection**

For a  $V_{\text{BUS}}$  short circuit, the switch is expected to withstand such a condition for at least 24 hours. The SGM7223 has specially designed circuitry which prevents unintended signal bleed through as well as guaranteed system reliability during a power-down,

over-voltage condition. The protection has been added to the common pins (D+, D-).

#### **Power-On Protection**

The USB 2.0 specification also notes that the USB device should be capable of withstanding a  $V_{\text{BUS}}$  short during transmission of data. This modification works by limiting current flow back into the  $V_{+}$  rail during the over-voltage event so current remains within the safe operating range. In this application, the switch passes the full 5.25V input signal through to the selected output, while maintaining specified off isolation on the un-selected pins.

### SGM7223 USB 2.0 Signal Quality Compliance Tests

Figures 1 and 2 show the test results for USB eye diagram tests. A summary of the USB tests is provided in Table 1. The SGM7223 passes the high speed signal quality, eye diagram and jitter tests.

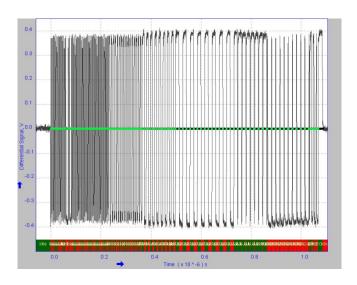


Figure 1. Waveform Plot

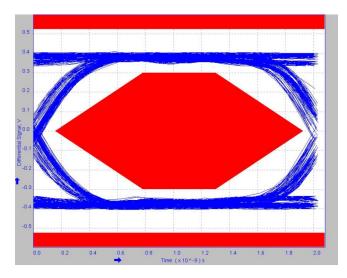


Figure 2. High Speed Signal Quality Eye Diagram Test  $(V_+ = 3.3V)$ 

# **APPLICATION INFORMATION (continued)**

Table 1. Summary of the USB 2.0 Signal Quality Tests Results

Measurement Name	MIN	MAX	Mean	pk-pk	Standard Deviation	RMS	Population	Status
Eye Diagram Test	-	-	-	-	-	-	-	Pass
Signal Rate	467.3807 Mbps	496.5449 Mbps	479.9494 Mbps	0.0000 bps	6.174360 Mbps	480.4821 Mbps	512	Pass
EOP Width	-	•	16.61442ns	•	-	-	1	Pass
EOP Width (Bits)	-	-	7.974082	-	-	-	1	Pass
Falling Edge Rate	1.100184 kV/µs	1.304518 kV/µs	1.187936 kV/µs	204.3340 V/μs	52.11665 V/μs	1.189068 kV/µs	107	Pass
Rising Edge Rate	1.058148 kV/µs	1.232657 kV/µs	1.137964 kV/µs	174.5099 V/μs	46.35985 V/μs	1.138899 kV/µs	108	Pass

#### Additional Information:

Consecutive Jitter range: -115.0ps to 71.20ps RMS Jitter 40.26ps KJ Paired Jitter range: -34.68ps to 29.00ps RMS Jitter 11.09ps JK Paired Jitter range: -30.42ps to 35.73ps RMS Jitter 12.11ps

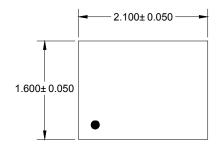
Rising Edge Rate: 1.137964kV/µs (Equivalent Rise Time = 562.41ps)
Falling Edge Rate: 1.187936kV/µs (Equivalent Fall Time = 538.75ps)

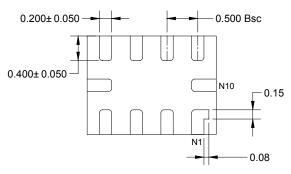
### **REVISION HISTORY**

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

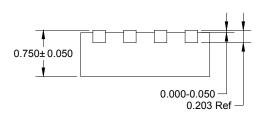
MAY 2016 - REV.A.1 to REV.A.2	Page
Added Recommended Land Pattern section	11
Added Tape and Reel Information section	12, 13
MAY 2011 - REV.A to REV.A.1	Page
Updated package name	All
Changes from Original (AUGUST 2008) to REV.A	Page
Changed from product preview to production data	All

# **PACKAGE OUTLINE DIMENSIONS** TQFN-2.1×1.6-10L



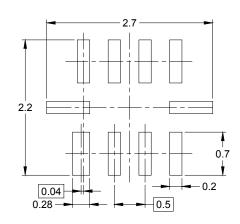


**TOP VIEW** 



**SIDE VIEW** 

**BOTTOM VIEW** 

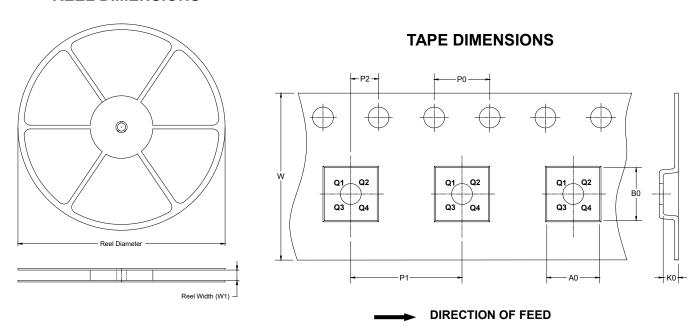


**RECOMMENDED LAND PATTERN** 

NOTE: All linear dimensions are in millimeters.

# TAPE AND REEL INFORMATION

### **REEL DIMENSIONS**

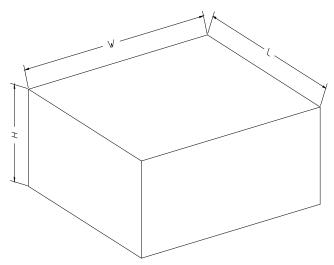


NOTE: The picture is only for reference. Please make the object as the standard.

### **KEY PARAMETER LIST OF TAPE AND REEL**

Package Type	Reel Diameter	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P0 (mm)	P1 (mm)	P2 (mm)	W (mm)	Pin1 Quadrant
TQFN-2.1×1.6-10L	7"	9.0	1.90	2.30	0.90	4.0	4.0	2.0	8.0	Q1

### **CARTON BOX DIMENSIONS**



NOTE: The picture is only for reference. Please make the object as the standard.

### **KEY PARAMETER LIST OF CARTON BOX**

Reel Type	Length (mm)	Width (mm)	Height (mm)	Pizza/Carton
7" (Option)	368	227	224	8
7"	442	410	224	18